University of Mumbai

Examination 2021 under cluster 5(Lead College: APSIT)

Examinations Commencing from 01st June 2021

Program: Electronics and Telecommunication Engineering

Curriculum Scheme: Rev2016

Examination: TE Semester VI

Course Code: ECCDLO 6021 and Course Name: Digital VLSI Design

Time: 2 hour

Max. Marks: 80

01	Choose the correct option for following questions. All the Questions are
QI.	compulsory and carry equal marks
1	
<u>l.</u>	Which of the following statement is not true?
Option A:	Two metal lines can cross each other at the same layer
Option B:	When a polysilicon crosses a diffusion region, it represents a MOSFET
Option C:	Stick diagrams do not represent dimensions of MOSFET
Option D:	Stick diagrams do not represent parasitic in the circuit
2.	what of the following is not a feature of Static CMOS design style?
Option A:	Low power consumption
Option B:	Smaller area requirement
Option C:	Implementation of complement expression
Option D:	Good noise margin
2	· · · · · · · · · · · · · · · · · · ·
5.	
	The above circuit is
Option A:	NOR gate
Option B:	NAND gate
Option C:	XOR gate
Option D:	AND gate
4.	Which of the following is not a dynamic design style
Option A:	Domino logic
Option B:	NORA logic
Option C:	C ² MOS logic
Option D:	Pseudo nMOS logic
5.	The loss of output voltage level due to charge sharing problem in dynamic CMOS

	design can be prevented using
Option A:	Voltage bootstrapping
Option B:	Evaluation transistor
Option C:	Weak pull-up
Option D:	Parallel output capacitor
6.	In a NOR based ROM, data bit '1' is stored using,
Option A:	Absence of a transistor
Option B:	Presence of a transistor
Option C:	Series combination of transistor
Option D:	Parallel combination of transistor
7.	SRAM stores data using,
Option A:	Charge on the capacitor
Option B:	Modulating threshold voltage of a MOSFET
Option C:	Magnetic field
Option D:	Cross coupled inverters
8.	What of the following is true about NAND flash and NOR flash,
Option A:	NOR flash has better fabrication density than NAND flash
Option B:	NOR flash have faster read operations
Option C:	In NAND flash, cells are connected in parallel
Option D:	NOR flash endure for more erase cycles than NAND flash
9.	Carry Select Adder overcomes latency by,
Option A:	Avoiding rippling of carry from LSB to MSB
Option B:	Aiding the propagation of carry bit around an adder
Option C:	Simultaneous MSB-half addition with both possible values of LSB-half carry
Option D:	Predicting the carry
10	
10.	What is the formula for calculating carry bit c_{i+1} in the addition of a_i and b_i using
	Carry Look Ahead Adder?
Option A:	
Option B:	$c_i \oplus p_i$
Option C:	$g_i + p_i c_i$
Option D:	$a_i \oplus b_i$
11	Which of the following is the best switchle for addition of 7 multiplic hit much and
11.	which of the following is the dest suitable for addition of / multi-bit numbers
Option R:	Carry Look Abood Adder
Option C:	Carry Look Aneau Adder
Option D:	Corry Save Adder
Option D.	
12	The output of 8X4 harrel shifter after performing 3 bit logical left shift operation
12.	on 11010111
Ontion A:	1101
Ontion R.	0101
Option C.	1011
Option D	0111
option D.	

Option A: Feature size Option B: Signal Integrity Option C: Compatibility with other IC technology Option D: Inter IC communication speed 14. Random skew, drift and jitter form the clock distribution network are proportional to Option A: The clock frequency Option D: The network delay Option D: Circuit architecture 15. The essence of ESD protection is, Option A: To provide a controlled discharge path for high voltage to avoid damaging of gate oxide Option D: To create a barrier to avoid damaging of gate oxide Option D: To create a barrier to avoid damaging of diffusion region Option D: To create a barrier to avoid damaging of diffusion region Option D: To create a barrier to avoid damaging of diffusion region Option D: To create a barrier to avoid damaging of diffusion region Option D: To create a barrier to avoid damaging of diffusion region Option B: Return path effect Option B: Return path effect Option D: Inter Symbolic Interference 16. Capacitive or inductive coupling causes interference called, Option B:
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Option C: Programmable AND plane and fixed OR plane
Option D: Programmable AND plane and programmable OR plane
18. FPGA stands for
Option A: Fast Programmable Gate Array
Option B: Field Programmable Gate Array
Option C: Fast Programmable Gate Arrangement
Option D: Field Programmable Gate Arrangement
19. What is the proper sequence of the steps to design a Custom Single Purpose
Processor Ontion A. III SM Controllor ESM Detenoth Design Connect the detenoth to controllor
Option A: HLSM-Controller FSM-Datapath Design-Connect the datapath to controller
Option C: HI SM Detenath Design Controllor ESM Connect the detenath to controller
Option D: HI SM Datapath Design Connect the datapath to controller Controller ESM
Option D. These Datapath Design-Connect the datapath to controller-Controller FSM
20 How does controller FSM differ from HI SM?
20. How does conducted 1'SW differ from 11LSW1; Option A: ESM have fewer states than ULSM
Option B: Condition for state transition in ESM is a signal status, whereas UI SM have

Option C:	FSM do not have external control inputs, HLSM have external control inputs
Option D:	In FSM state transition can happen without an event, in HLSM the transition can
	happen only on the occurrence of an event

Q2		
A	Solve any Two 05 mark	ks each
i.	Implement 4X4 NAND based ROM array to store '1001', '0011', '0 '0010' in the memory	101',
ii.	Implement 4:1 MUX using transmission gate	
iii.	Write HDL code for D Flip Flop with asynchronous 'Reset' input. If reset signal is '1', the output is '0'.	the
В	Solve any One 10 mark	s each
i.	Draw JK flip flop using CMOS and explain the working.	
ii.	Draw 3-T DRAM Cell and explain the following operations in brief	with
	appropriate diagram.	
	a) Write '1'	
	b) Write '0'	
	c) Read '1'	
	d) Read ''0	
Q3.		
А	Solve any Two 05 mark	ks each
1.	Explain ESD in brief Explain any one protection network with appro- diagram.	priate
ii.	Implement a Full Adder using PAL.	
iii.	Draw a 3 bit array multiplier.	
В	Solve any One 10 mark	s each
i.	Explain the Carry Look Ahead Adders in brief. Write the expression	for
	carry generate and propagate circuit for 4 bit adder. Implement the sa	ime
	using domino logic.	
ii.	Design a 'Laser Based Distance Measurement System' using the RT	Ĺ
	design process.	